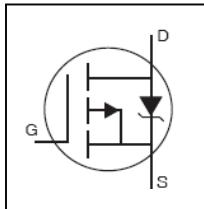


Features

- Advanced Planar Technology
- P-Channel MOSFET
- Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

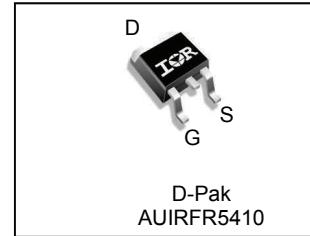
Description

Specifically designed for Automotive applications, this Cellular Planar design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.



HEXFET® Power MOSFET

V_{DSS}	-100V
R_{DS(on)} max.	0.205Ω
I_D	-13A



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRFR5410	D-Pak	Tube	75	AUIRFR5410
		Tape and Reel Left	3000	AUIRFR5410TRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-13	A
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-8.2	
I _{DM}	Pulsed Drain Current ①	-52	
P _D @ T _C = 25°C	Maximum Power Dissipation	66	W
	Linear Derating Factor	0.53	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	194	mJ
I _{AR}	Avalanche Current ①	-8.4	A
E _{AR}	Repetitive Avalanche Energy ①	6.3	
dv/dt	Peak Diode Recovery dv/dt③	-5.0	V/ns
T _J	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R _{θJC}	Junction-to-Case ⑤⑧	—	1.9	°C/W
R _{θJA}	Junction-to-Ambient (PCB Mount) ⑦	—	50	
R _{θJA}	Junction-to-Ambient	—	110	

HEXFET® is a registered trademark of Infineon.

*Qualification standards can be found at www.infineon.com

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	-100	—	—	V	$V_{GS} = 0V, I_D = -250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	-0.12	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = -1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.205	Ω	$V_{GS} = -10V, I_D = -7.8\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	-2.0	—	-4.0	V	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
g_{fs}	Forward Trans conductance	3.2	—	—	S	$V_{DS} = -25V, I_D = -7.8\text{A}$ ④
I_{DSS}	Drain-to-Source Leakage Current	—	—	-25	μA	$V_{DS} = -100V, V_{GS} = 0V$
		—	—	-250		$V_{DS} = -80V, V_{GS} = 0V, T_J = 150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{GS} = -20V$
	Gate-to-Source Reverse Leakage	—	—	100		$V_{GS} = 20V$

Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

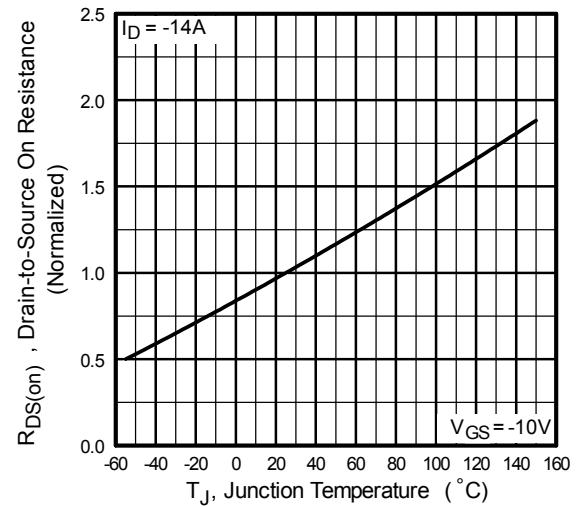
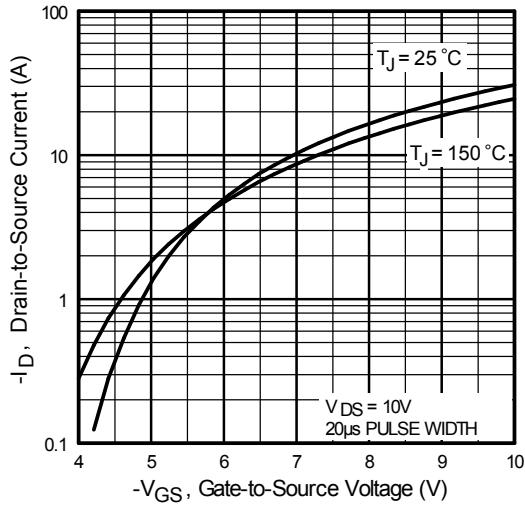
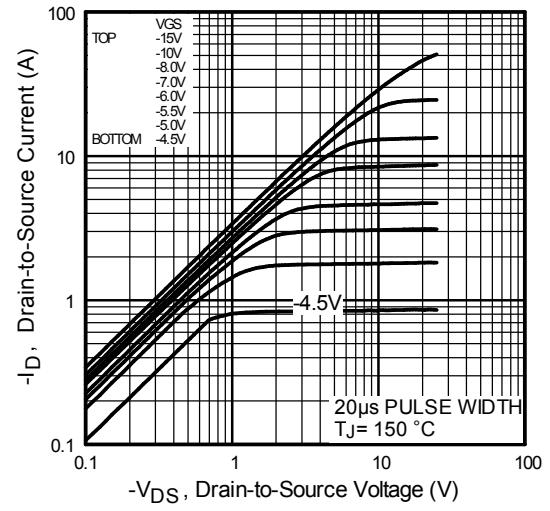
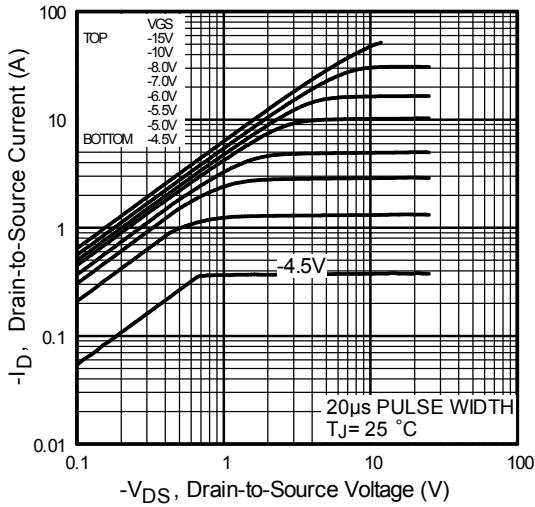
Q_g	Total Gate Charge	—	—	58	nC	$I_D = -8.4\text{A}$ $V_{DS} = -80V$ $V_{GS} = -10V$ ④⑥
Q_{gs}	Gate-to-Source Charge	—	—	8.3		
Q_{gd}	Gate-to-Drain Charge	—	—	32		
$t_{d(on)}$	Turn-On Delay Time	—	15	—		$V_{DD} = -50V$ $I_D = -8.4\text{A}$
t_r	Rise Time	—	58	—	ns	$R_G = 9.1\Omega$ $R_D = 6.2\Omega$ ④⑥
$t_{d(off)}$	Turn-Off Delay Time	—	45	—		
t_f	Fall Time	—	46	—		
L_D	Internal Drain Inductance	—	4.5	—		Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—	nH	
C_{iss}	Input Capacitance	—	760	—	pF	$V_{GS} = 0V$
C_{oss}	Output Capacitance	—	260	—		$V_{DS} = -25V$
C_{rss}	Reverse Transfer Capacitance	—	170	—		$f = 1.0\text{MHz}$ ⑥

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)	—	—	-13	A	MOSFET symbol showing the integral reverse p-n junction diode.
	Pulsed Source Current (Body Diode) ①	—	—	-52		
V_{SD}	Diode Forward Voltage	—	—	-1.6	V	$T_J = 25^\circ\text{C}, I_S = -7.8\text{A}, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	—	130	190	ns	$T_J = 25^\circ\text{C}, I_F = -8.4\text{A}$ $dI/dt = 100\text{A}/\mu\text{s}$ ④
Q_{rr}	Reverse Recovery Charge	—	650	970	nC	
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^\circ\text{C}$, $L = 6.4\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -7.8\text{A}$ (See fig. 12)
- ③ $I_{SD} \leq -7.8\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$.
- ④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑤ This is applied for I-PAK, LS of D-PAK is measured between lead and center of die contact.
- ⑥ Uses IRF9530N data and test conditions.
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑧ R_θ is measured at T_J approximately 90°C



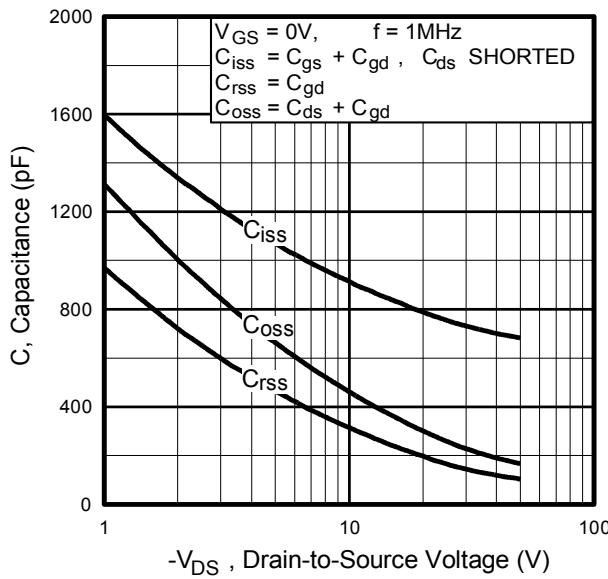


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

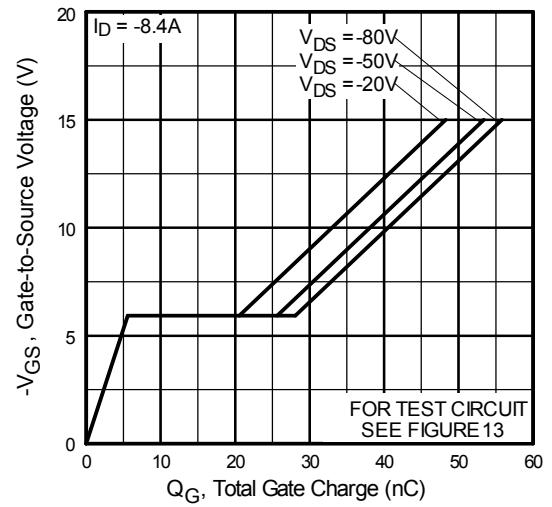


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

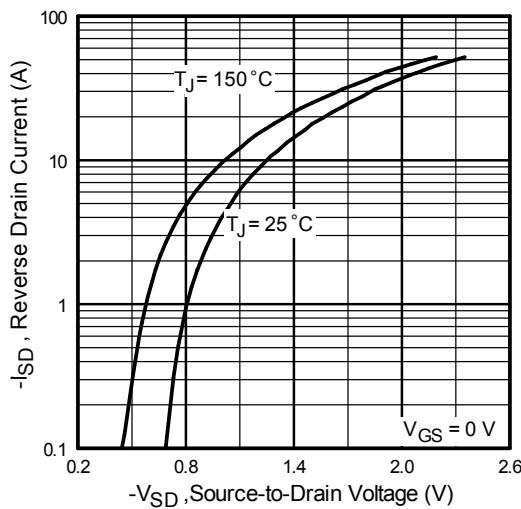


Fig. 7 Typical Source-to-Drain Diode
Forward Voltage

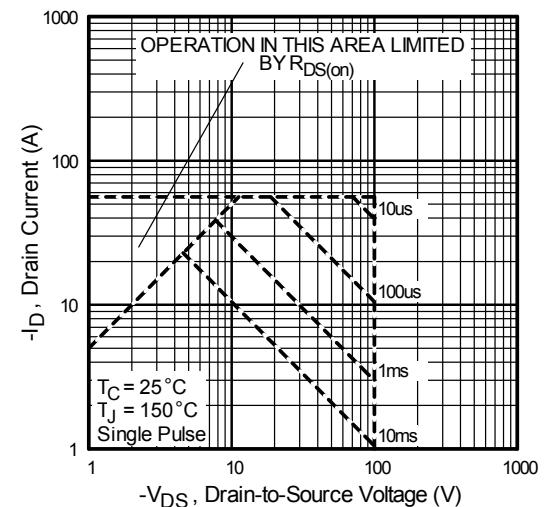


Fig 8. Maximum Safe Operating Area

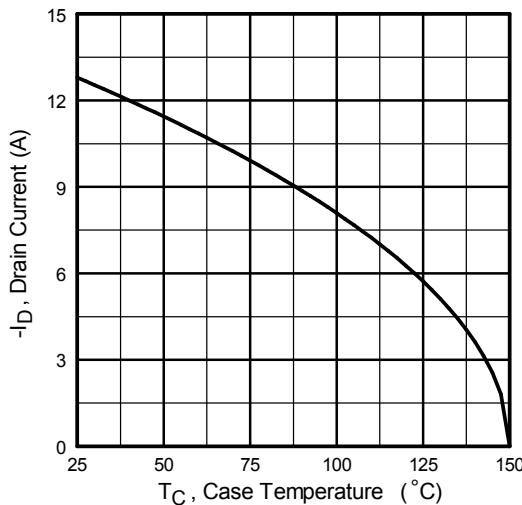


Fig 9. Maximum Drain Current Vs. Case Temperature

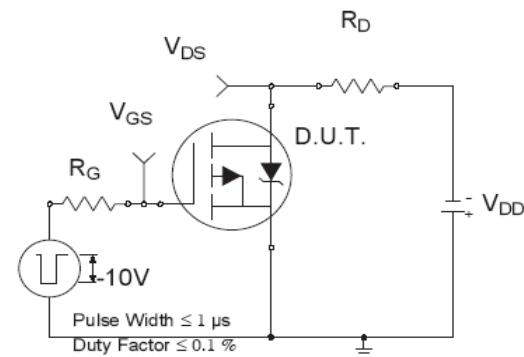


Fig 10a. Switching Time Test Circuit

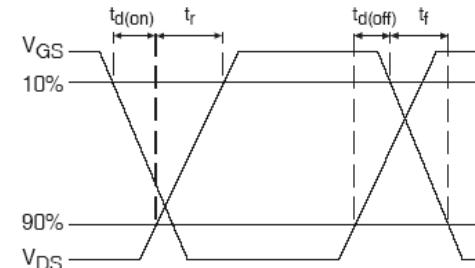


Fig 10b. Switching Time Waveforms

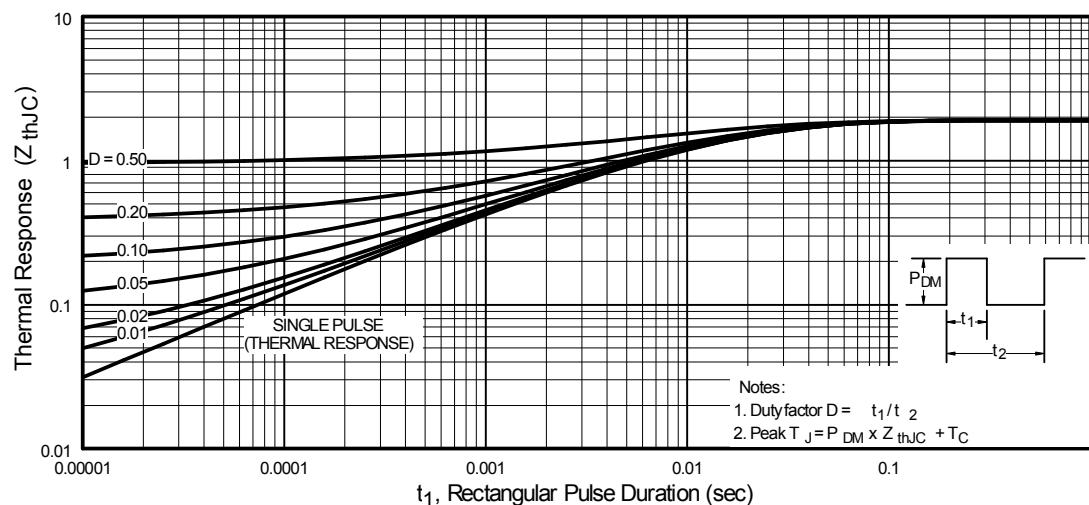


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

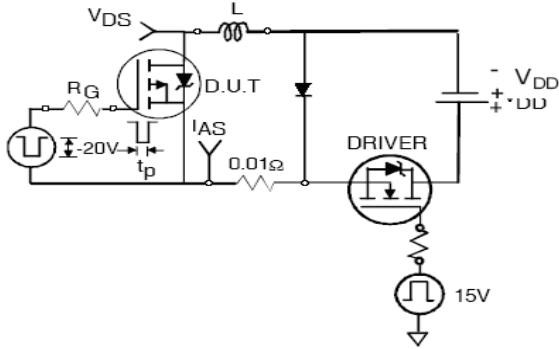


Fig 12a. Unclamped Inductive Test Circuit

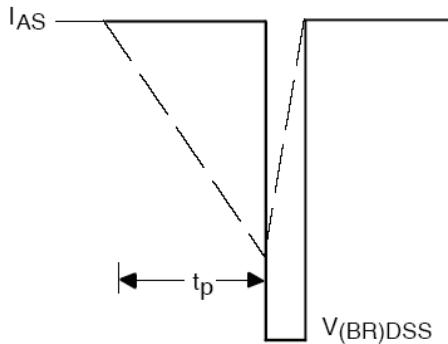
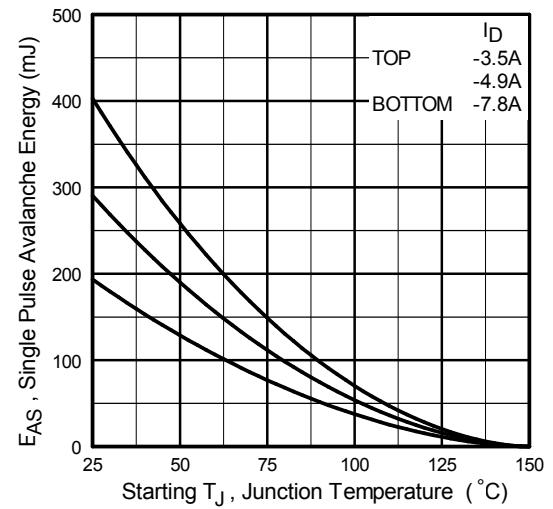


Fig 12b. Unclamped Inductive Waveforms

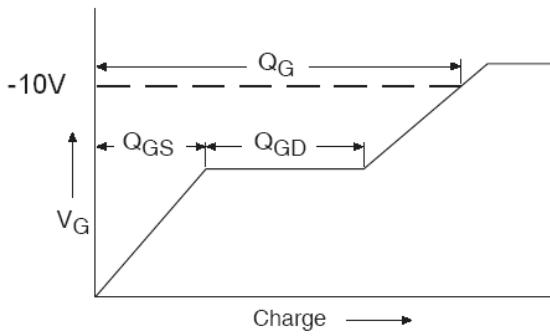


Fig 13a. Gate Charge Waveform

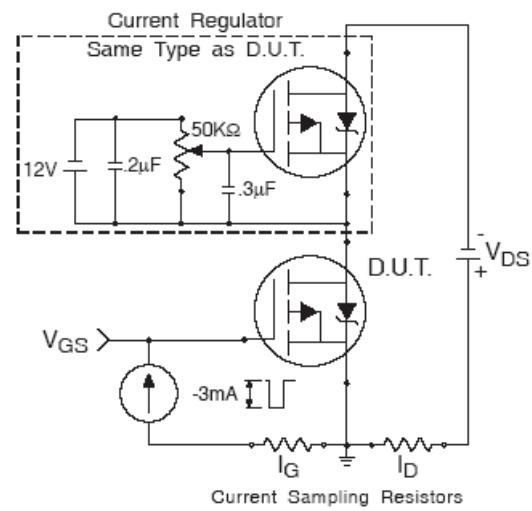
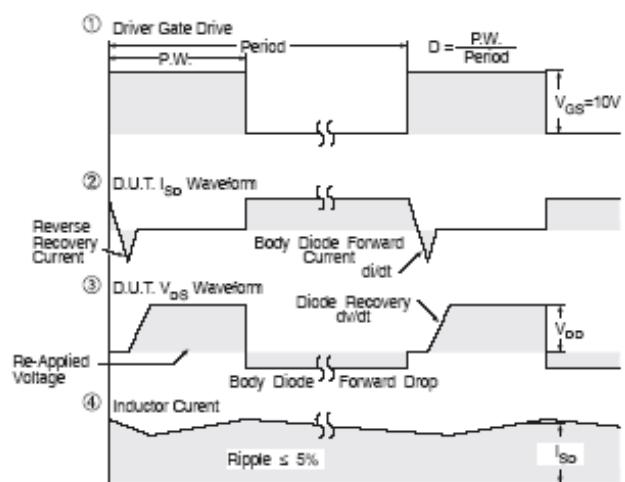
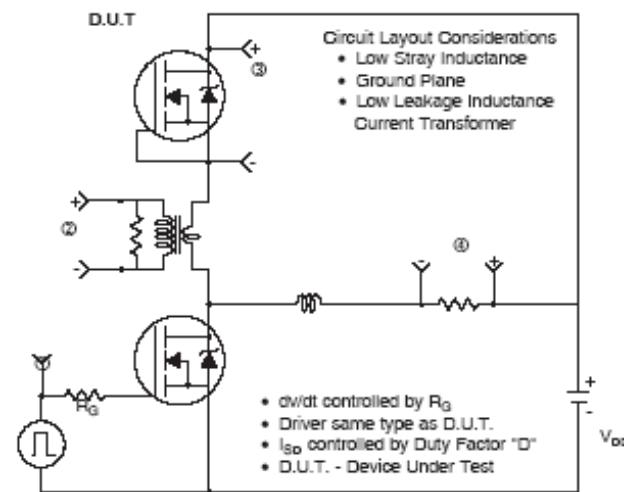


Fig 13b. Gate Charge Test Circuit

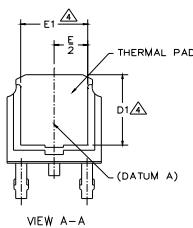
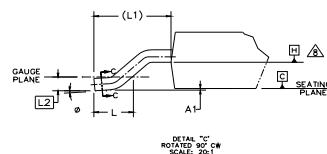
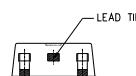
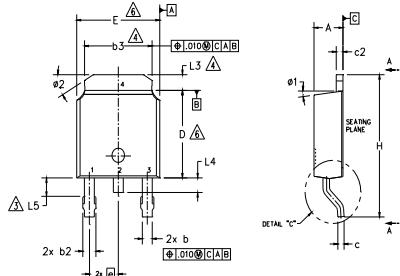
Peak Diode Recovery dv/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

Fig 14. Peak Diode Recovery dv/dt Test Circuit for P-Channel HEXFET® Power MOSFETs

D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))



NOTES

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
 - 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
 - LEAD DIMENSION UNCONTROLLED IN L5.
 - DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
 - 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
 - DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
 - DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
 - DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
 - 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	2.18	2.39	.086	.094		
A1	—	0.13	—	.005		
b	0.64	0.89	.025	.035		
b1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
c	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	—	.205	—	4	
E	6.35	6.73	.250	.265	6	
E1	4.32	—	.170	—	4	
e	2.29	BSC	.090	BSC		
H	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	—	1.02	—	.040		
L5	1.14	1.52	.045	.060	3	
Ø	0*	10*	0*	10*		
Ø1	0*	15*	0*	15*		
Ø2	25*	35*	25*	35*		

LEAD ASSIGNMENTS

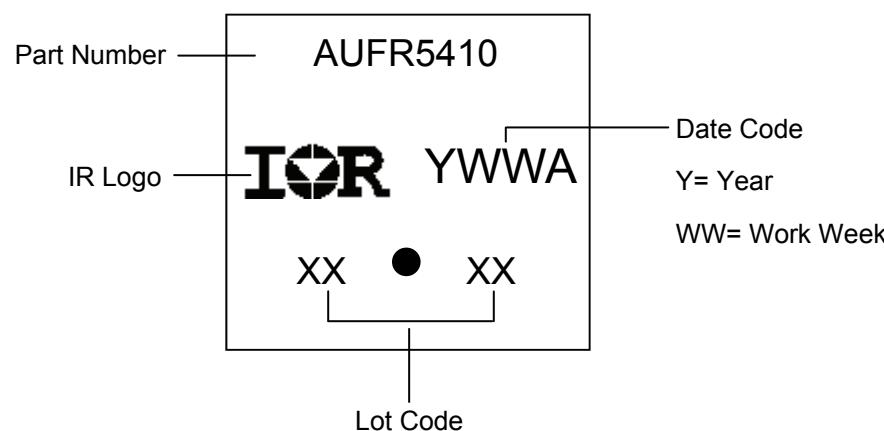
HEXFET

1. - GATE
 2. - DRAIN
 3. - SOURCE
 4. - DRAIN

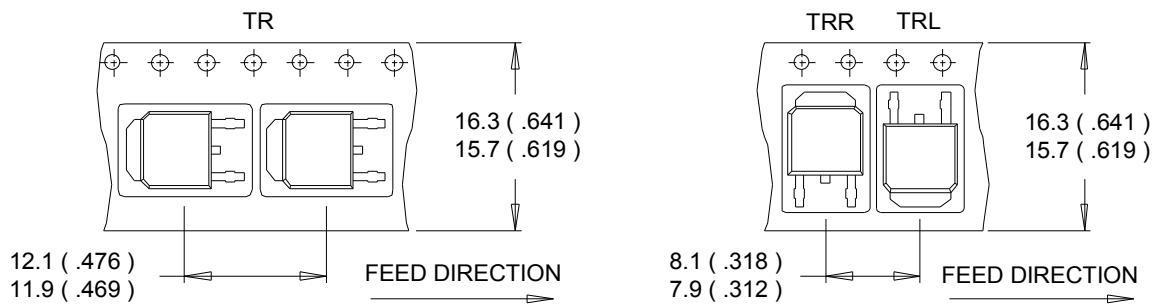
IGBT & CoPAK

- 1.- GATE
 - 2.- COLLECTOR
 - 3.- Emitter
 - 4 - COLLECTOR

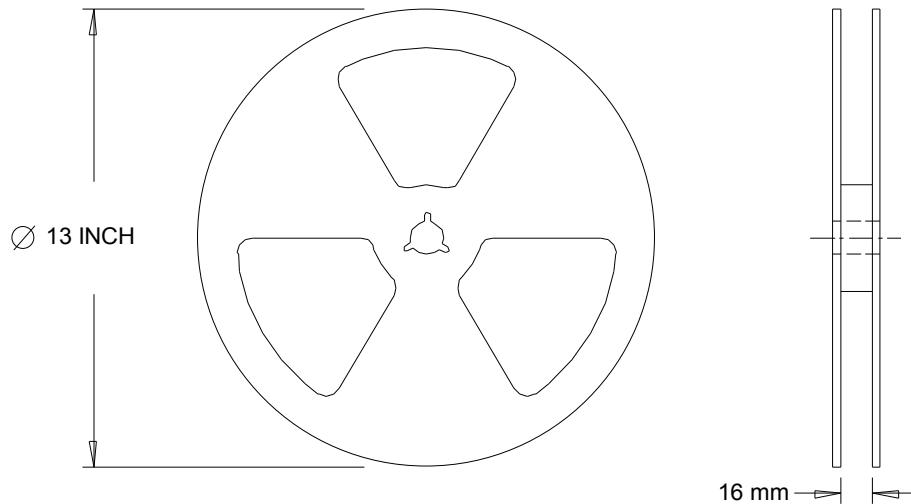
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))**NOTES :**

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.

**NOTES :**

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Qualification Information

Qualification Level		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level		D-Pak	MSL1
ESD	Machine Model	Class M2 (+/- 200V) [†] AEC-Q101-002	
	Human Body Model	Class H1B (+/- 1000V) [†] AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 1125V) [†] AEC-Q101-005	
RoHS Compliant		Yes	

[†] Highest passing voltage.

Revision History

Date	Comments
12/2/2015	<ul style="list-style-type: none"> • Updated datasheet with corporate template • Corrected ordering table on page 1.

Published by

Infineon Technologies AG
81726 München, Germany

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